

Strain dependence of photoluminescence of individual carbon nanotubes.

Pavel N. Nikolaev¹, Tonya K. Leeuw², Dmitri A. Tsyboulski², Sergei M. Bachilo², R. Bruce Weisman² and Sivaram Arepalli¹

1. ERC Inc and NASA Johnson Space Center, Houston, TX.

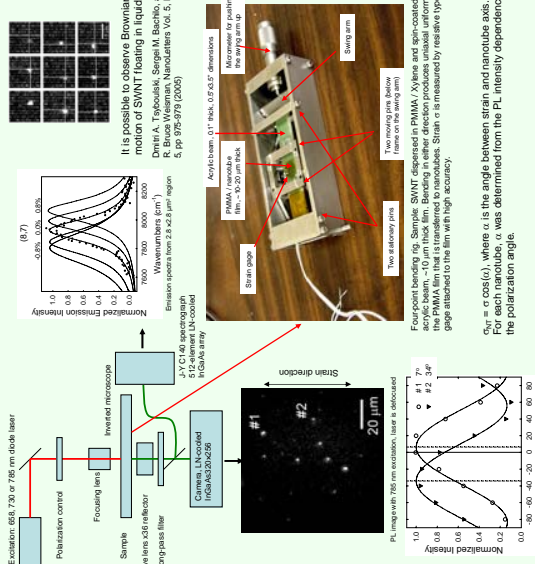
2. Rice University, Houston, TX

We have investigated strain dependence of photoluminescence (PL) spectra of single wall carbon nanotubes (SWNT). Nanotubes were sparsely dispersed in a thin PMMA film applied to acrylic bar, and strained in both compression and extension by bending this bar in either direction in a homebuilt four-point bending rig. The average surface strain was measured with high accuracy by a resistive strain gage applied on top of the film. The near – infrared imaging and spectroscopy were performed on the inverted microscope equipped with high numerical aperture reflective objective lens and InGaAs CCD cameras. PL was excited with a diode laser at either 658, 730 or 785 nm, linearly polarized in the direction of the strain. We were able to measure (n,m) types and orientation of individual nanotubes with respect to strain direction and strain dependence of their PL maxima. It was found that PL peak shifts with respect to the values measured in SDS micelles are a sum of three components. First, a small environmental shift due to difference in the dielectric constant of the surrounding media, that is constant and independent of the nanotube type. Second, shift due to isotropic compression of the film during drying. Third, shifts produced by the uniaxial loading of the film in the experiment. Second and third shifts follow expression based on the first-order expansion of the TB hamiltonian. Their magnitude is proportional to the nanotube chiral angle and strain, and direction is determined by the nanotube quantum number. PL strain dependence measured for a number of various nanotube types allows to estimate TB carbon-carbon transfer integral.

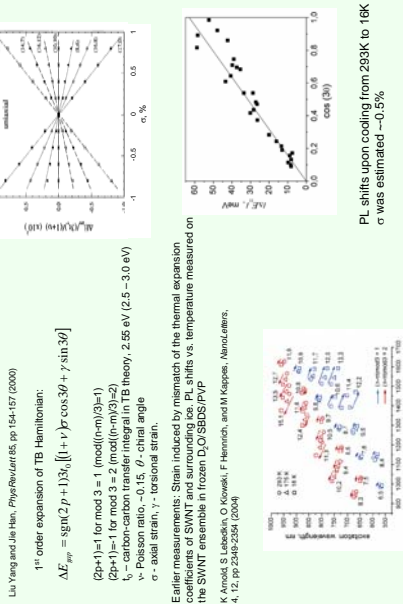
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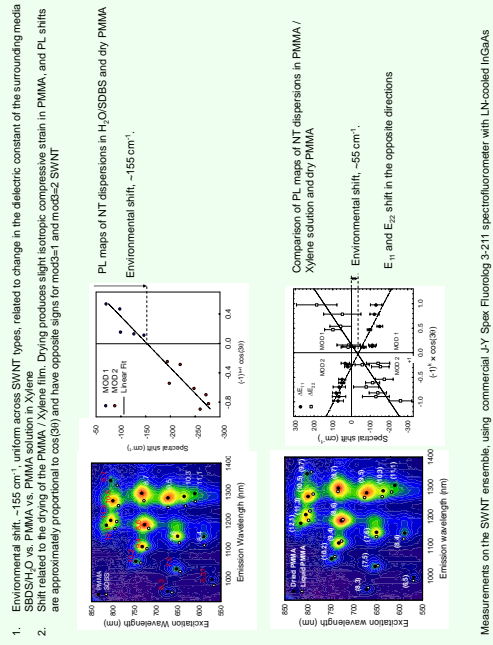
PL observations on individual nanotubes.



Theoretical prediction of the bandgap shift under strain:



Origin of the initial PL shifts

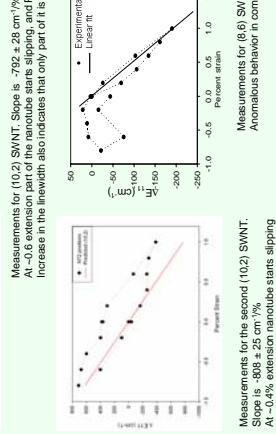
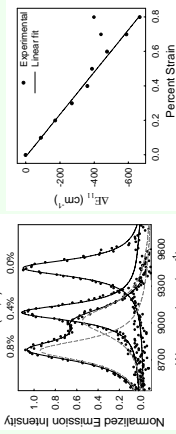
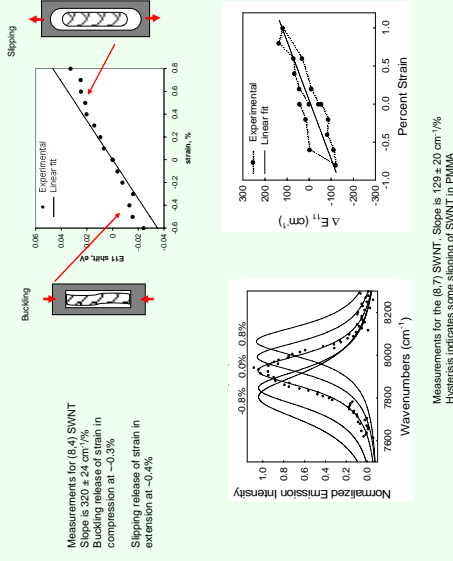


1. Environmental shift ~155 cm⁻¹, uniform across SWNT types, related to change in the dielectric constant of the surrounding media SBDShJO vs. PMMA vs. PMMA solution in Xylene
2. Shift related to the drying of the PMMA / Xylene film. Drying produces slight isotropic compressive strain in PMMA, and PL shifts are approximately proportional to $\cos(3\theta)$ and have opposite signs for mod3=1 and mod3=2 SWNT

PL maps of NT dispersions in H₂O/DBS and dry PMMA / Xylene solution and dry PMMA. Environmental shift, ~155 cm⁻¹.

Comparison of PL maps of NT dispersions in PMMA / Xylene solution and dry PMMA. Environmental shift, ~55 cm⁻¹. E₁₁ and E₂₂ shift in the opposite directions

Measurements



Determining C-C transfer integral t_0 from experiment

